

Notice of References Cited	Application/Control No. 10/718,400	Applicant(s)/Patent Under Reexamination YANAVI, AURA	
	Examiner Thuy Dao	Art Unit 2192	Page 1 of 2

U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Integrating Metrics and Models for Software Risk Assessment", Hudepohl et al., 1996, 6 pages. Full text of IDS document filed November 20, 2003, cited in page 1 of 4.
	V	"Reliability Analysis of Large Software Systems: Defect Data Modeling", Levendel., 1990, 12 pages. Full text of IDS document filed November 20, 2003, cited in page 1 of 4.
	W	"Understanding the Sources of Software Defects: A Filtering Approach", Wohlin et al., 2000, 9 pages. Full text of IDS document filed November 20, 2003, cited in page 2 of 4.
	X	"Defect Prevention through Defect Prediction: A Case Study at Infosys", Mohapatra et al., 2001, 13 pages. Full text of IDS document filed November 20, 2003, cited in page 3 of 4.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Thuy Dao	Art Unit 2192	Page 2 of 2

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	U	"A Critique of Software Defect Prediction Models", Fenton et al., 1999, 15 pages. Full text of IDS document filed November 20, 2003, cited in page 4 of 4.
	V	"Understanding and Predicting the Process of Software Maintenance Releases", Basili et al., 1996, 11 pages. Full text of IDS document filed November 20, 2003, cited in page 4 of 4.
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	X	

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